

Notice of References Cited

Application/Control No.

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Applicant(s)/Patent Under

Reexamination

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Examiner

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Art Unit

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,139,793-A	10-2000	VANDERWAL	422/1
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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FOREIGN PATENT DOCUMENTS

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